# **μPARSET - DISCRETE HIGH-VOLUME TESTER**

# Eliminates lengthy test times

Gain short tester times and increase production at a lower total cost of ownership. Built as a modular parameter test system for discrete semiconductor devices with up to 12 leads, the Discrete High-Volume Tester enables high throughput. Flexible hardware and software make the Tester suitable for all wafer testing, final testing, acceptance or quality testing, and device characterization tasks. µPARSET software gathers data about measured devices and produces various insights. It is handler and prober agnostic, equipped to connect to any prober or tester. High accuracy leads to a narrow spread in test results and better products. It can connect up to four handlers when floor space is limited.



# Key features

#### Target segments

- Back-end final test
- Wafer Test

#### High performance

- Handler and prober agnostic
- · Multi-site testing
- 1 to 4 handlers
- Short test times
- Pin electronics (voltage and current measurement on all pins simultaneously)
- Maximum number of pins: (FT and AT/QT): 6 or 12 pins
- High-quality diagnostics and calibration
- High accuracy

# Test heads

- Current amplifier for fast leakage measurement
- Short and open pins close to DUT
- Dedicated test hardware

#### Embedded software

- User-definable parameters
- Visual ITEC: user-definable operator interface
- Automatic multi-site expansion
- Scope function
- V and I waveforms and timing on all channels
- Real-time diagnostics
- Curve traces

#### Extendable software

- Equipment control for multiple test cells
- Post-processing
- Dynamic part average test
- Static part average test
- Moving limits
- Nearest neighbourhood residual

## Extreme flexibility options:

- µPFM: floating mV meter (30 mV / 300 mV / 3 V)
- DCM: digital capacitance meter (0.3/3/30/300 pF)
- µMUX: multiplexer 4 x 24 pins for multi-site test

#### **Specifications**

### Maximum supply and current per channel

• 400 V/3 A

## Small footprint

• 600 x 665 x 1235mm

#### Other

- Extendable test heads for adding handlers (max 4)
- Maximum: 12 leads
- Voltage: 220-240 VAC +/- 5%, 1-phase
- Current: Fused on 16 A
- Frequency: 50/60 Hz +/- 0.5 Hz
- Handler Interface: GPIB, TTL, RS232, TCP/IP
- Optional SECS/GEM interface following SEMI standard



Follow us on LinkedIn: www.linkedin.com/company/itecequipment



www.ITECequipment.com

# © 2023 ITEC

All rights reserved. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. No liability will be accepted by the publisher for any consequence of its use. Publication thereof does not convey nor imply any license under trademark- or other industrial or intellectual property rights.

